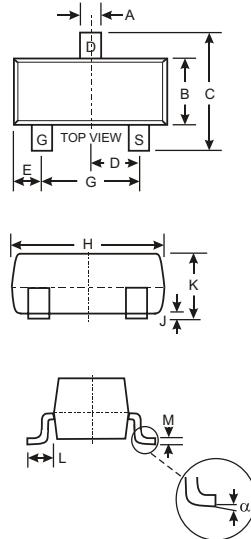


## N-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

### Features

- High density cell design for Low R<sub>D(on)</sub>.
- Voltage controlled small signal switch.
- Rugged and reliable.
- High saturation current capability.
- ESD protected.
- Marking Code:72K

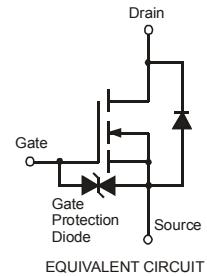


SOT-23		
Dim	Min	Max
A	0.37	0.51
B	1.20	1.40
C	2.30	2.50
D	0.89	1.03
E	0.45	0.60
G	1.78	2.05
H	2.80	3.00
J	0.013	0.10
K	0.903	1.10
L	0.45	0.61
M	0.085	0.180
$\alpha$	0°	8°

All Dimensions in mm

### Maximum Ratings @ T<sub>A</sub> = 25°C unless otherwise specified

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V <sub>DS</sub>	60	V
Gate-source Voltage	V <sub>GSS</sub>	$\pm 20$	V
Drain Current	I <sub>D</sub>	300	mA
Pulsed Drain Current A	I <sub>DM</sub>	1.5	A
Total Power Dissipation @ T <sub>A</sub> =25°C	P <sub>D</sub>	350	mW
Thermal Resistance Junction-to-Ambient @ Steady State B	R <sub>θJA</sub>	357	°C/W
Junction and Storage Temperature Range	T <sub>J,TSTG</sub>	-55~+150	°C



A. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ .  
B. Device mounted on FR-4 PCB, 1 inch x 0.85 inch x 0.062 inch.



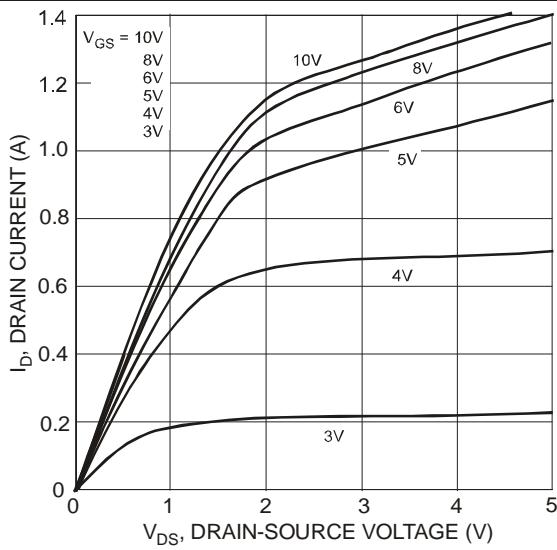
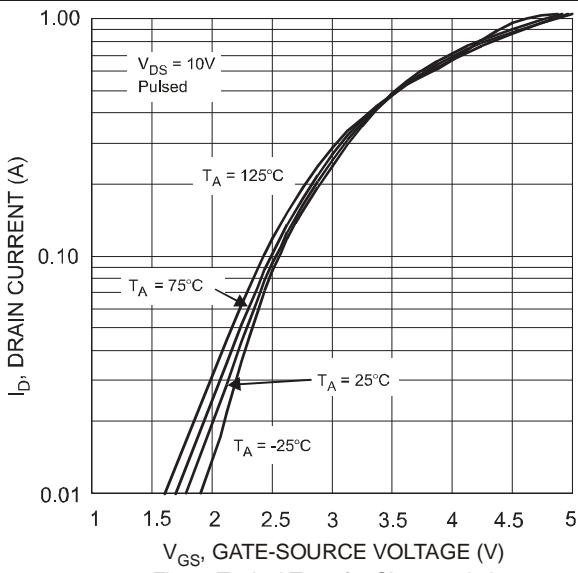
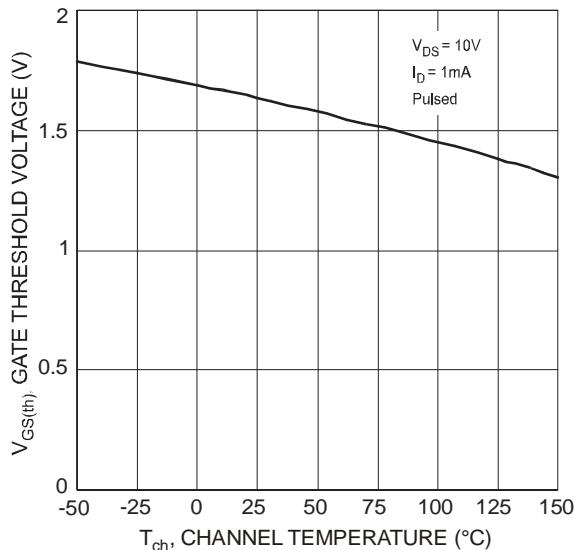
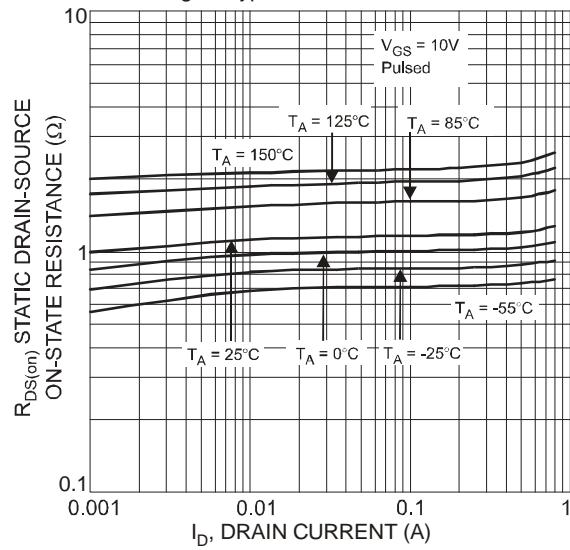
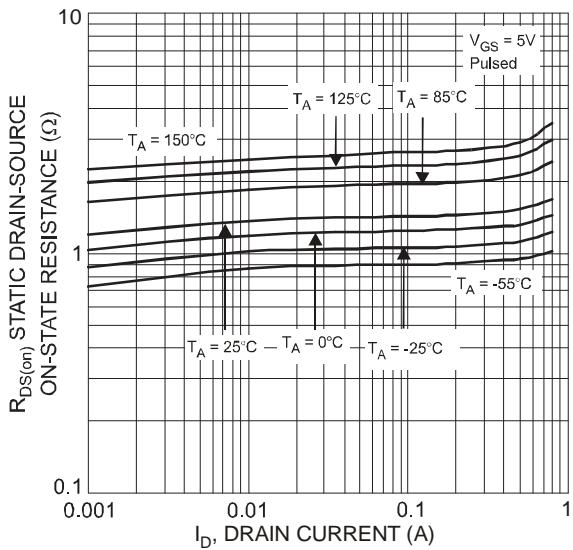
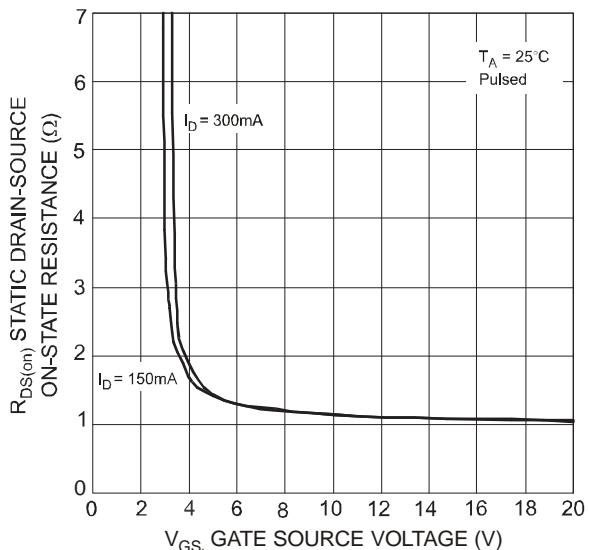
HAICHUANG SEMI

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## N-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

Electrical Characteristics @  $T_A = 25^\circ\text{C}$  unless otherwise specified

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BVDSS	VGS= 0V, ID=250μA	60			V
Zero Gate Voltage Drain Current	IDSS	VDS=60V, VGS=0V			1	μA
Gate-Body Leakage Current	IGSS	VGS= ±20V, VDS=0V			±10	μA
Gate Threshold Voltage	VGS(th)	VDS= VGS, ID=250μA	0.8	1.5	3.0	V
Static Drain-Source On-Resistance	RDS(ON)	VGS= 10V, ID=450mA		2.0	3.5	Ω
		VGS= 4.5V, ID=200mA		2.8	4.5	
Diode Forward Voltage	VSD	IS=450mA, VGS=0V			1.2	V
Maximum Body-Diode Continuous Current	IS				300	mA
<b>Dynamic Parameters</b>						
Input Capacitance	Ciss	VDS=60V, VGS=0V, f=1MHZ		18		pF
Output Capacitance	Coss			12		
Reverse Transfer Capacitance	Crss			7		
<b>Switching Parameters</b>						
Total Gate Charge	Qg	VGS=10V, VDS=60V, ID=0.3A		1.7	2.4	nC
Turn-on Delay Time	tD(on)	VGS=10V, VDD=30V, ID=300mA, RGEN=6Ω		5		ns
Turn-off Delay Time	tD(off)			17		
Reverse recovery Time	trr	VGS=0V, IS=300mA, VR=25V, dIS/dt=- 100A/μs		30		ns

**N-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR**
**TYPICAL TRANSIENT CHARACTERISTICS**

**Fig. 1** Typical Output Characteristics

**Fig. 2** Typical Transfer Characteristics

**Fig. 3** Gate Threshold Voltage vs. Channel Temperature

**Fig. 4** Static Drain-Source On-Resistance vs. Drain Current

**Fig. 5** Static Drain-Source On-Resistance vs. Drain Current

**Fig. 6** Static Drain-Source On-Resistance vs. Gate-Source Voltage

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